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10005637**PATENT NUMBER and  
ISSUE DATE****U.S. UTILITY Patent Application**

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10005637	12/05/2001	260	527.5	2870	Le

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 438 12 2512 SKR 7529

**\*\*CONTINUING DATA VERIFIED:****\*\* FOREIGN APPLICATIONS VERIFIED:**

JAPAN 2000-377116 12/12/2000

PG-FUB <input type="checkbox"/> DO NOT PUBLISH <input checked="" type="checkbox"/>	RESCIND <input type="checkbox"/>	ATTORNEY DOCKET NO M2013-43
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no	35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no	U.S. DEPT. OF COMM./PAT. & TM-PTO-136LR (Rev. 11-94)
Verified and Acknowledged Examiner's initials		
TITLE : Defect inspection method for three-dimensional object		

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claim for O.G.
		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drawn	Fig.s Drawn
		Print Fig.	
<b>TERMINAL</b>		<b>Primary Examiner</b>	
		<b>PREPARED FOR ISSUE</b>	
		Application Examiner	
<b>DISCLAIMER</b>			
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